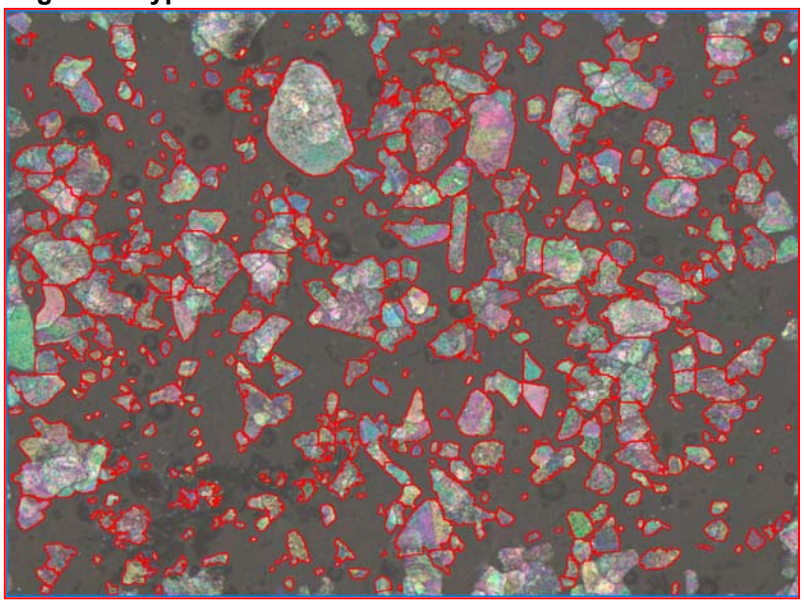
Particle Sizing Analysis

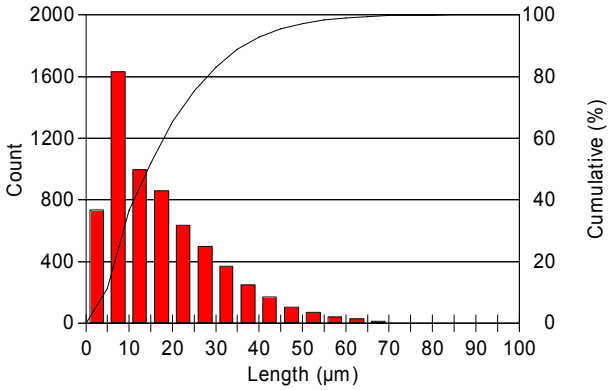
Compagny: Clemex Technologies Inc.
Date: 2005-Dec-21
User: Myriam Savard
Sample ID: Business Card #1

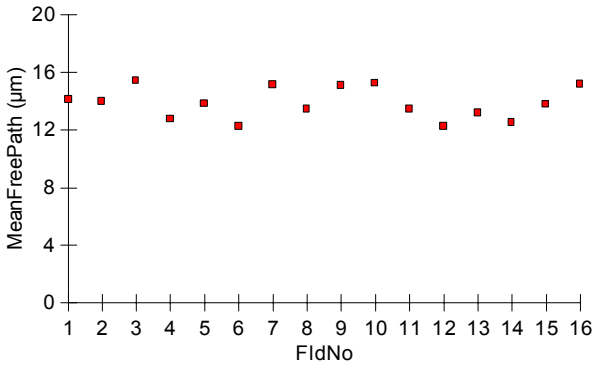
Magnification: 200x
Calibration: 0.4055 µm/pixel
 # Fields: 16
 # Particles: 6486

Figure 1: Typical field of view.



Comments:
This analysis was performed using a multi layer grab since the business card was a bit wavy. Anything that had an area smaller than 6 microns was eliminated from the analysis. Features sectioned by the field of view were also rejected. An automatic separation was applied so some features may be overseparated and some others may remain connected. Results shown below were validated using the Data Browser and the Mapping View tool.





Minimum:	3.09	microns	12 µm
Maximum:	84.70	microns	15 µm
Mean:	17.82	microns	13.9 µm
Std. Dev.:	13.12	microns	1.11 µm
D10:	4.75	microns	
D50:	14.20	microns	
D90:	36.21	microns	

Approved by:

Image Analysis Steps

Figure 1: Original image at 200x (0.4055 microns/pixel)

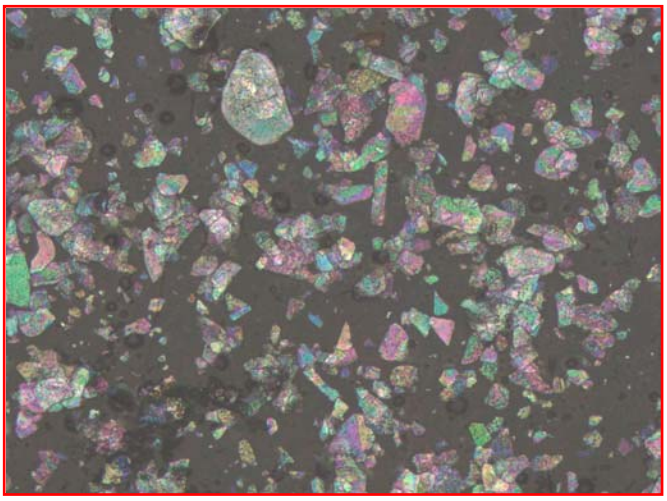


Figure 2: Particles as binarized into red bitplane and measured.

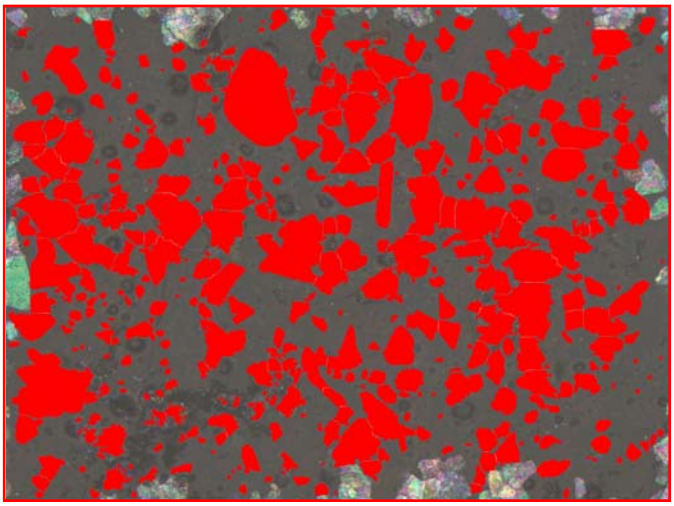


Figure 3: Same as previous but in outline mode.